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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1914		SERIAL NO. Priority 09/651,815	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Jerome Michael Eldridge			
				FILING DATE Priority August 30, 2000		GROUP Priority 2813	
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	3,954,523	05/76	Magdo et. al.			
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						Yes	No
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EXAMINER					DATE CONSIDERED		
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-1914SERIAL NO.  
Priority 09/651,815LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Jerome Michael EldridgeFILING DATE  
Priority August 30, 2000GROUP  
Priority 2813

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	AP							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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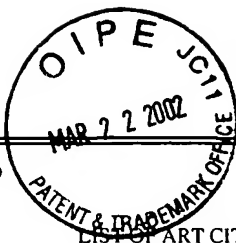
EXAMINER

*Harold S. Seltzer*

DATE CONSIDERED

*5/3/03*

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Sheet 1 of 1

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1914		SERIAL NO. 10/044,206		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Jerome Michael Eldridge				
				FILING DATE January 11, 2002		GROUP 2813		
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EXAMINER 				DATE CONSIDERED 5/3/05				
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